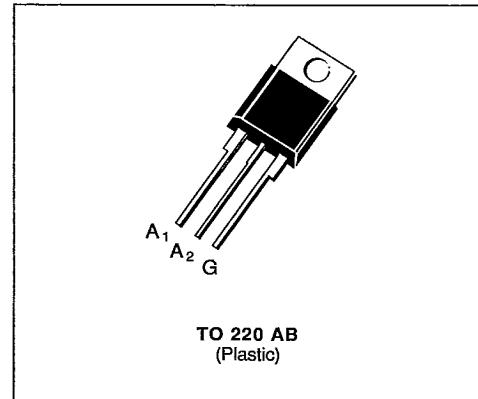


TRIACS

- GLASS PASSIVATED CHIP
- I_GT SPECIFIED IN FOUR QUADRANTS

**DESCRIPTION**

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value		Unit
I _{T(RMS)}	RMS on-state Current (360° conduction angle)	T _C = 90 °C	15	A
I _{TSM}	Non Repetitive Surge Peak on-state Current (T _J initial = 25 °C - Half sine wave)	t = 8.3 ms	157	A
		t = 10 ms	150	
I ² t	I ² t Value for Fusing	t = 10 ms	112.5	A ² s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive F = 50 Hz	10	A/μs
		Non Repetitive	50	
T _{stg} T _J	Storage and Operating Junction Temperature Range	- 40 to 150 - 40 to 125		°C °C

Symbol	Parameter	BTB 15-					Unit
		200B	400B	600B	700B	800B	
V _{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) I_G = 750 mA dI_G/dt = 1 A/μs

(2) T_J = 125 °C.

THERMAL RESISTANCES

Symbol	Parameter	Value		Unit
R _{th (j-a)}	Junction to Ambient	60		°C/W
R _{th (j-c) DC}	Junction to Case for DC	2.66		°C/W
R _{th (j-c) AC}	Junction to Case for 360° Conduction Angle (F = 50 Hz)	2		°C/W

GATE CHARACTERISTICS (maximum values)

$P_{GM} = 40 \text{ W}$ ($t_p = 10 \mu\text{s}$) $I_{GM} = 4 \text{ A}$ ($t_p = 10 \mu\text{s}$)
 $P_{G(AV)} = 1 \text{ W}$ $V_{GM} = 16 \text{ V}$ ($t_p = 10 \mu\text{s}$)

T-25-15

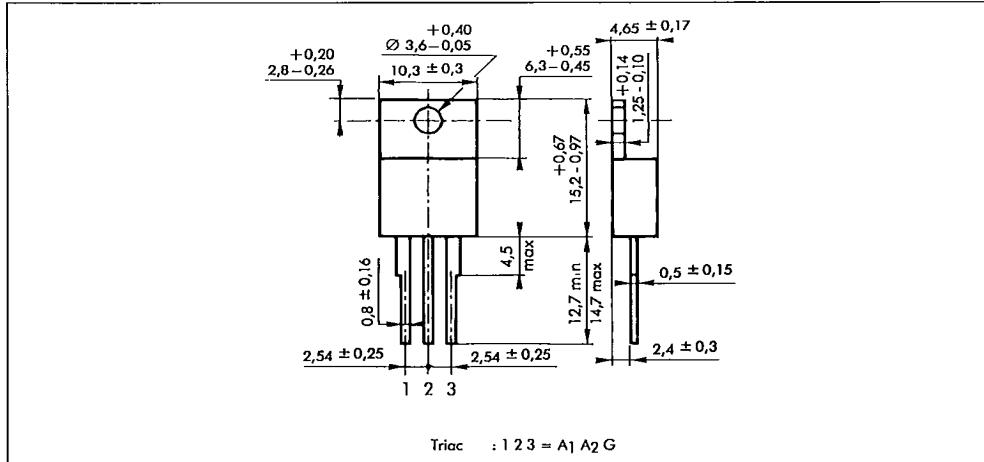
ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III IV			50	mA
	Pulse Duration > 20 μs						75	
V_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			1.5	V
	Pulse Duration > 20 μs							
V_{GD}	$T_j = 125^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				50	mA
I_L	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$I_G = 150 \text{ mA}$	I-III-IV II		50		mA
	Pulse Duration > 20 μs					100		
V_{TM}^*	$T_j = 25^\circ\text{C}$	$I_{TM} = 21 \text{ A}$	$t_p = 10 \text{ ms}$				1.5	V
I_{DRM}^*	V_{DRM} Specified		$T_j = 25^\circ\text{C}$				0.01	mA
			$T_j = 125^\circ\text{C}$				2	
dv/dt^*	$T_j = 125^\circ\text{C}$ Gate Open Linear Slope up to $V_D = 67\% V_{DRM}$				250	500		V/ μs
$(dv/dt)_c^*$	$T_C = 90^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 21 \text{ A}$		10			V/ μs
t_{gt}	$T_j = 25^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 21 \text{ A}$	I-II-III-IV		2		μs
	$I_G = 500 \text{ mA}$	$dI_G/dt = 3.5 \text{ A}/\mu\text{s}$						

* For either polarity of electrode A₂ voltage with reference to electrode A₁.

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

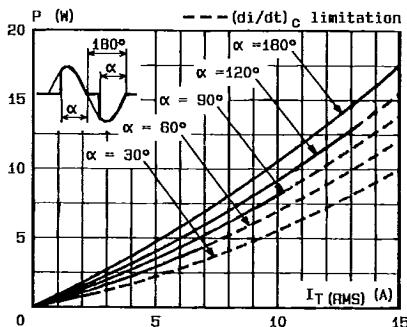


Fig.1 - Maximum mean power dissipation versus RMS on-state current ($F = 60$ Hz).

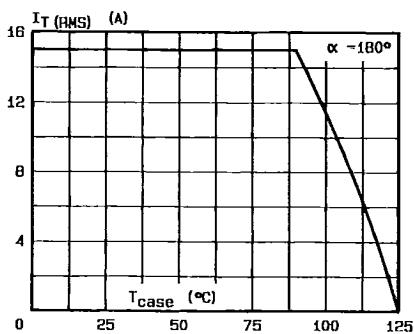


Fig.3 - RMS on-state current versus case temperature.

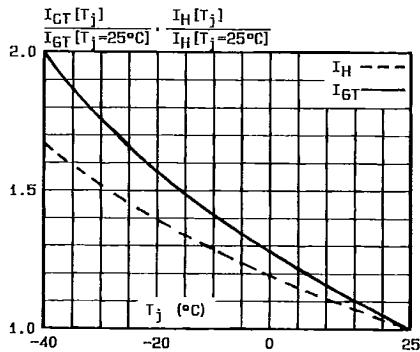


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

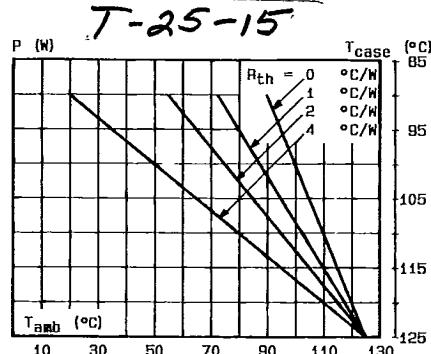


Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

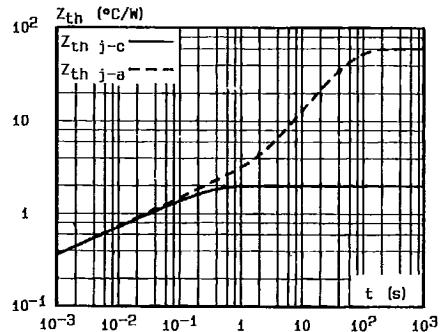


Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

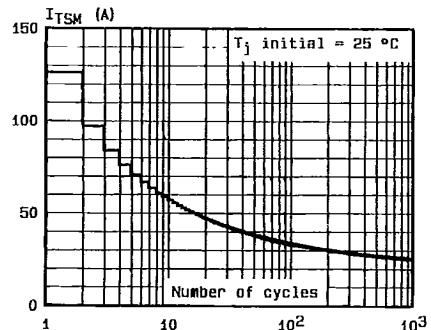


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

S G S-THOMSON

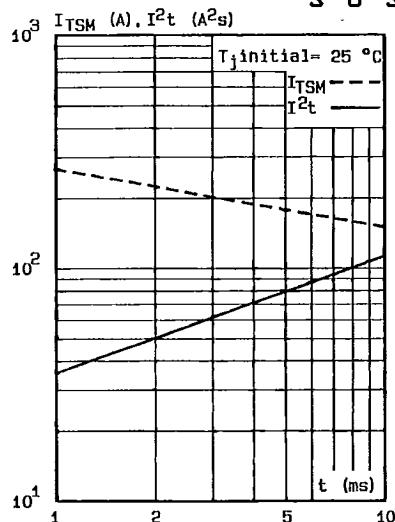


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width: $t \leq 10\text{ms}$, and corresponding value of I^2t .

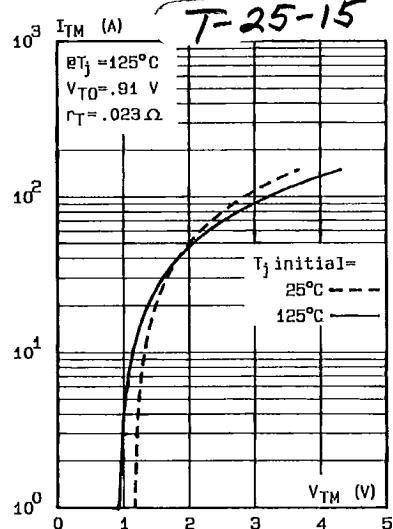


Fig.8 - On-state characteristic (maximum values).